PSMN1R3-30YL

N-channel 30 V 1.3 m Ω logic level MOSFET in LFPAK

Rev. 02 — 25 June 2009

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel MOSFET in LFPAK package qualified to 150 °C. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

1.2 Features and benefits

- Advanced TrenchMOS provides low RDSon and low gate charge
- High efficiency gains in switching power convertors
- Improved mechanical and thermal characteristics
- LFPAK provides maximum power density in a Power SO8 package

1.3 Applications

- DC-to-DC converters
- Lithium-ion battery protection
- Load switching

- Motor control
- Server power supplies

1.4 Quick reference data

Table 1. Quick reference

| Symbol | Parameter | Conditions | | Min | Тур | Max | Unit |
|----------------------|--|---|-----|-----|------|-----|------|
| V_{DS} | drain-source voltage | $T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$ | | - | - | 30 | V |
| I _D | drain current | T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u> ; | [1] | - | - | 100 | A |
| P _{tot} | total power dissipation | T _{mb} = 25 °C; see <u>Figure 2</u> | | - | - | 121 | W |
| Tj | junction temperature | | | -55 | - | 150 | °C |
| Avalance | he ruggedness | | | | | | |
| E _{DS(AL)S} | non-repetitive drain-source avalanche energy | V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 100 A; V_{sup} ≤ 30 V; R_{GS} = 50 Ω ; unclamped | | - | - | 383 | mJ |
| Dynamic | Dynamic characteristics | | | | | | |
| Q_{GD} | gate-drain charge | $V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A};$ | | - | 9.3 | - | nC |
| $Q_{G(tot)}$ | total gate charge | V _{DS} = 12 V; see <u>Figure 13</u> ; see Figure 14 | | - | 46.6 | - | nC |



Table 1. Quick reference ... continued

| Symbol | l Parameter | Conditions | Min | Тур | Max | Unit |
|-------------------|----------------------------------|--|-----|------|-----|------|
| Static c | haracteristics | | | | | |
| R _{DSon} | drain-source on-state resistance | $V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 100 \text{ °C}; \text{ see } \frac{\text{Figure } 12}{}$ | - | - | 1.8 | mΩ |
| | | $V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 17}{\text{ constant}}$ | - | 1.04 | 1.3 | mΩ |

^[1] Continuous current is limited by package.

2. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol | | | |
|-----|--------|-----------------------------------|---------------------------|----------------|--|--|--|
| 1 | S | source | | _ | | | |
| 2 | S | source | | D | | | |
| 3 | S | source | | G (F) | | | |
| 4 | G | gate | | | | | |
| mb | D | mounting base; connected to drain | 1 2 3 4 SOT1023 (LFPAK2) | mbb076 S | | | |

3. Ordering information

Table 3. Ordering information

| Type number | Package | | | | |
|--------------|---------|---|---------|--|--|
| | Name | Description | Version | | |
| PSMN1R3-30YL | LFPAK2 | Plastic single-ende surface-mounted package (LFPAK2); 4 leads | SOT1023 | | |

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | | Min | Max | Unit |
|----------------------|--|---|-----|-----|-----|------|
| V_{DS} | drain-source voltage | T _j ≥ 25 °C; T _j ≤ 150 °C | | - | 30 | V |
| V_{DGR} | drain-gate voltage | $T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$ | | - | 30 | V |
| V_{GS} | gate-source voltage | | | -20 | 20 | V |
| I_D | drain current | $V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$ | [1] | - | 100 | Α |
| | | V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u> | [1] | - | 100 | Α |
| I_{DM} | peak drain current | $t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see <u>Figure 3</u> | | - | 923 | Α |
| P _{tot} | total power dissipation | T _{mb} = 25 °C; see <u>Figure 2</u> | | - | 121 | W |
| T _{stg} | storage temperature | | | -55 | 150 | °C |
| Tj | junction temperature | | | -55 | 150 | °C |
| $T_{sld(M)}$ | peak soldering temperature | | | - | 260 | °C |
| Source-dr | ain diode | | | | | |
| I _S | source current | $T_{mb} = 25 ^{\circ}C;$ | [1] | - | 100 | Α |
| I _{SM} | peak source current | $t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$ | | - | 923 | Α |
| Avalanche | ruggedness | | | | | |
| E _{DS(AL)S} | non-repetitive drain-source avalanche energy | V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 100 A; $V_{sup} \le$ 30 V; R_{GS} = 50 Ω; unclamped | | - | 383 | mJ |

[1] Continuous current is limited by package.

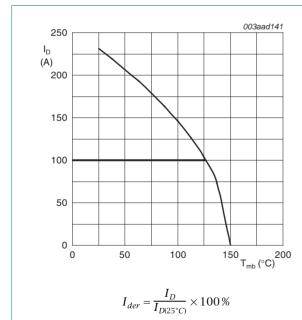


Fig 1. Normalized continuous drain currnet as a function of mounting base temperature

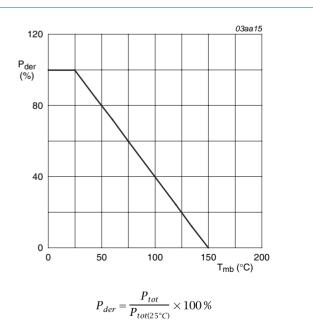
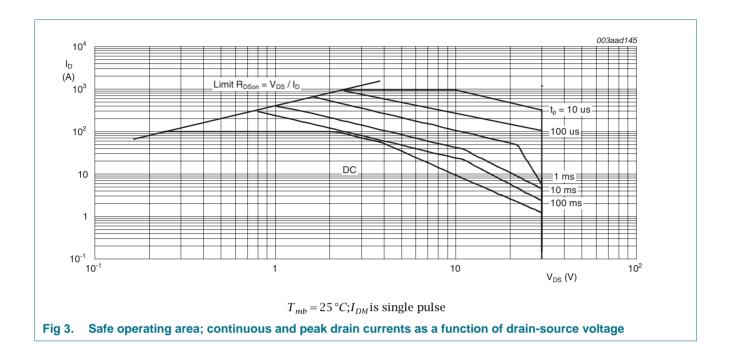


Fig 2. Normalized total power dissipation as a function of mounting base temperature

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5. Thermal characteristics

Thermal characteristics Table 5.

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|---|--------------|-----|-----|------|------|
| $R_{th(j\text{-}mb)}$ | thermal resistance from junction to mounting base | see Figure 4 | - | 0.4 | 1.03 | K/W |

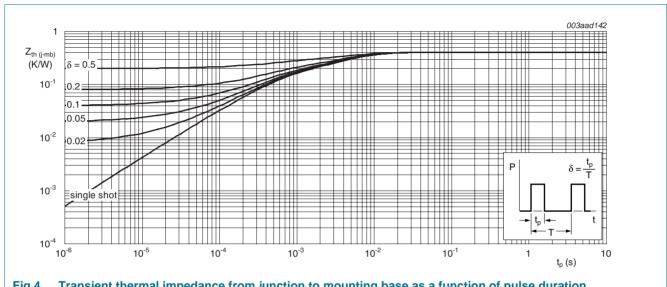


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 6. Characteristics

| Table 6. | Characteristics | | | | | |
|------------------------|-----------------------------------|--|------|------|------|------|
| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
| Static cha | racteristics | | | | | |
| $V_{(BR)DSS}$ | drain-source | $I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$ | 30 | - | - | V |
| | breakdown voltage | $I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^{\circ}C$ | 27 | - | | |
| $V_{GS(th)}$ | gate-source threshold voltage | $I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see <u>Figure 10</u> ; see <u>Figure 11</u> | 1.3 | 1.7 | 2.15 | V |
| | | $I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 150$ °C; see <u>Figure 10</u> | 0.65 | - | - | V |
| | | $I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see <u>Figure 10</u> | - | - | 2.45 | V |
| I _{DSS} | drain leakage current | $V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | - | 1 | μΑ |
| | | $V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$ | - | - | 100 | μΑ |
| I_{GSS} | gate leakage current | $V_{GS} = 15 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | - | 100 | nA |
| | | $V_{GS} = -15 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | - | 100 | nA |
| R _{DSon} | drain-source on-state resistance | $V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 17 | - | 1.43 | 1.95 | mΩ |
| | | $V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 100 \text{ °C};$ see <u>Figure 12</u> | - | - | 1.8 | mΩ |
| | | $V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 150 \text{ °C};$ see Figure 12 | - | 1.9 | 2.8 | mΩ |
| | | $V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 17 | - | 1.04 | 1.3 | mΩ |
| R_G | gate resistance | f = 1 MHz | - | 0.89 | - | Ω |
| Dynamic | characteristics | | | | | |
| $Q_{G(tot)}$ | total gate charge | $I_D = 25 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 10 \text{ V}$; see Figure 13; see Figure 14 | - | 100 | - | nC |
| | | I _D = 0 A; V _{DS} = 0 V; V _{GS} = 10 V | - | 90 | - | nC |
| | | $I_D = 25 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$; see Figure 13; see Figure 14 | - | 46.6 | - | nC |
| Q_{GS} | gate-source charge | $I_D = 25 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$; see Figure 13; see Figure 14 | - | 17.9 | - | nC |
| Q _{GS(th)} | pre-threshold gate-source charge | $I_D = 25 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$; see Figure 13 | - | 11 | - | nC |
| Q _{GS(th-pl)} | post-threshold gate-source charge | | - | 6.9 | - | nC |
| Q_{GD} | gate-drain charge | $I_D = 25 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$; see Figure 13; see Figure 14 | - | 9.3 | - | nC |
| V _{GS(pl)} | gate-source plateau voltage | V _{DS} = 12 V; see <u>Figure 13</u> ; see <u>Figure 14</u> | - | 2.53 | - | V |
| C _{iss} | input capacitance | $V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ | - | 6227 | - | pF |
| C _{oss} | output capacitance | $T_j = 25$ °C; see Figure 15 | - | 1415 | - | pF |
| C _{rss} | reverse transfer capacitance | | - | 619 | - | pF |

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Table 6. Characteristics ... continued

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|---------------------|-----------------------|---|-----|------|-----|------|
| $t_{d(on)}$ | turn-on delay time | V_{DS} = 12 V; R_L = 0.5 Ω ; V_{GS} = 4.5 V; | - | 64 | - | ns |
| t _r | rise time | $R_{G(ext)} = 5.6 \Omega$ | - | 108 | - | ns |
| t _{d(off)} | turn-off delay time | | - | 106 | - | ns |
| t _f | fall time | | - | 52 | - | ns |
| Source-d | rain diode | | | | | |
| V_{SD} | source-drain voltage | $I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 16 | - | 0.88 | 1.2 | V |
| t _{rr} | reverse recovery time | $I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/s}; V_{GS} = 0 \text{ V};$ | - | 46 | - | ns |
| Q _r | recovered charge | $V_{DS} = 20 \text{ V}$ | - | 53 | - | nC |

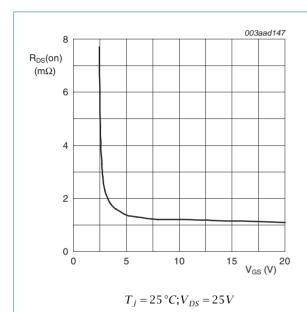


Fig 5. Drain-source on-state resistance as a function of gate-source voltage; typical values.

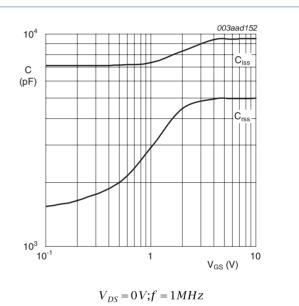


Fig 6. Input and reverse transfer capacitances as a function of gate-source voltage; typical values

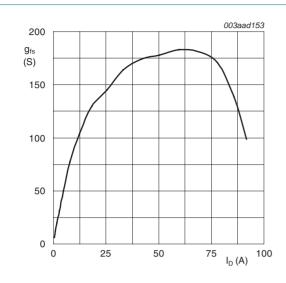


Fig 7. Forward transconductance as a function of drain current; typical values

 $T_j = 25 \,^{\circ}C; V_{DS} = 25 V$

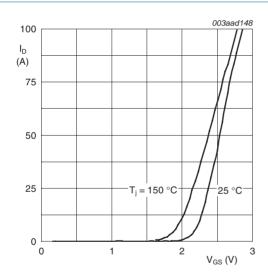


Fig 9. Transfer characteristics: drain current as a function of gate-source voltage; typical valuesvalues

 $V_{DS} > I_D \times R_{DSon}$

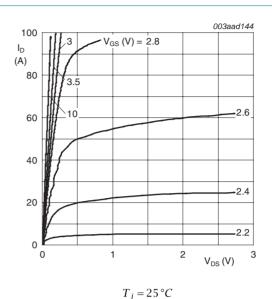


Fig 8. Output characteristics: drain current as a function of drain-source voltage; typical values

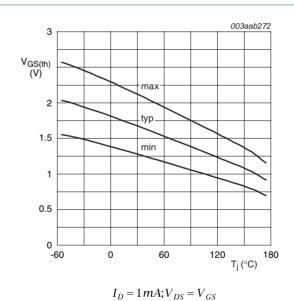
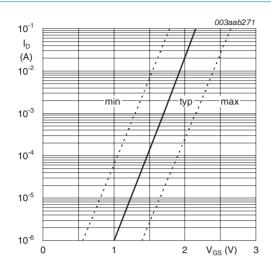


Fig 10. Gate-source threshold voltage as a function of junction temperature

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 $T_j = 25 \,^{\circ}C; V_{DS} = 5 \, V$

Fig 11. Sub-threshold drain current as a function of gate-source voltage

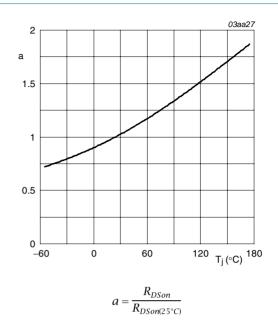


Fig 12. Normalized drain-source on-state resistance factor as a function of junction temperature

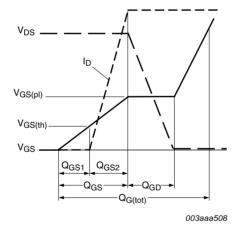


Fig 13. Gate charge waveform definitions

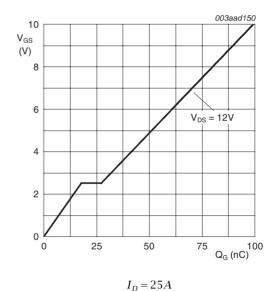


Fig 14. Gate-source voltage as a function of gate charge; typical values

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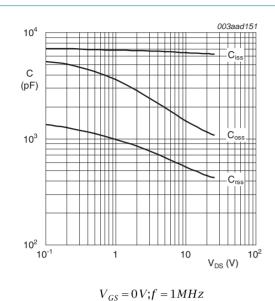


Fig 15. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

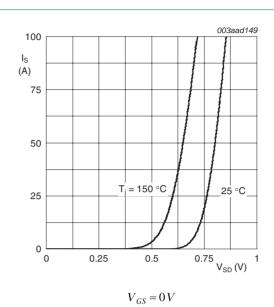
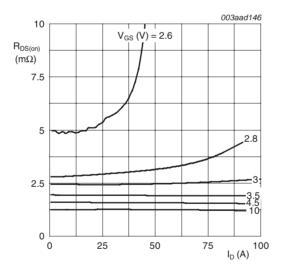


Fig 16. Source current as a function of source-drain voltage; typical values

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 $T_i = 25 \,^{\circ}C$

Fig 17. Drain-source on-state resistance as a function of drain current; typical values

Package outline

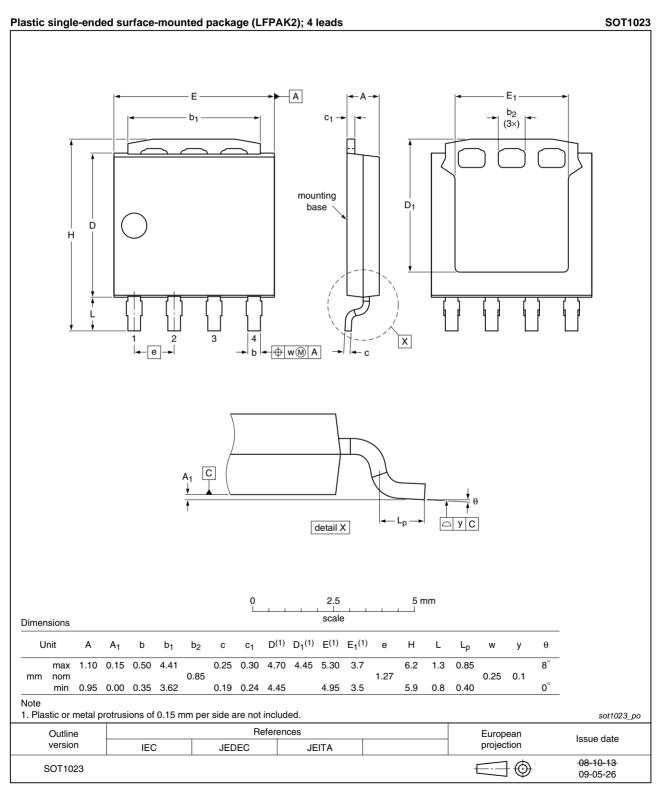


Fig 18. Package outline SOT1023; Package outline



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Revision history

Table 7. **Revision history**

Product data sheet

| Document ID | Release date | Data sheet status | Change notice | Supersedes |
|----------------|---------------------------------|---------------------------|---------------|----------------|
| PSMN1R3-30YL_2 | 20090625 | Product data sheet | - | PSMN2R3-30YL_1 |
| Modifications: | Status char | nged from objective to pr | oduct. | |
| | Various cha | anges to content. | | |
| PSMN1R3-30YL_1 | 20090528 | Objective data sheet | - | - |

9. Legal information

9.1 Data sheet status

| Document status [1][2] | Product status[3] | Definition |
|--------------------------------|-------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
| Product [short] data sheet | Production | This document contains the product specification. |

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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